

IN THE SPECIFICATION

Please further amend the paragraph appearing from page 77, line 14 to page 78, line 2, as follows (the below paragraph incorporates the amendment made thereto in the Preliminary Amendment filed on February 11, 2004):

Furthermore, it was found out that no region having high resistance did not exist in the carbon films 15 as a result of observation through an interatomic force/tunnel microscope having an interatomic force microscope probe (also referred to as an “Atomic Force Microscope (AFM)”) which was made electrically conductive so that an electrical conductivity distribution of a sample could be measured with the sample kept in contact with the probe. Furthermore, the probe was kept in contact with the carbon films 15 disposed on the electrically conductive film 14 during the measurement. An evaluation was made of specific resistance of the carbon film in a direction of width of the film ~~provided a result not higher than 0.001  $\Omega$ m taken from the probe to the electrically~~ conductive film provided a result not higher than 0.001  $\Omega$ m. Comparison of this value with that of a carbon film 15 which was formed without irradiation with electrons indicated a variation exceeding a place.

Please amend the paragraph appearing from page 80, line 20 to page 81, line 5, as follows:

Furthermore, it was found out that no region having high resistance did not exist in the carbon films 76 and 78 as a result of observation through an interatomic

force/tunnel microscope having a probe of an interatomic force microscope which was made electrically conductive as in Example 1 so that the microscope can measure an electrical conductivity distribution of a sample. Furthermore, an evaluation of specific resistance of the carbon film in a direction of width provided a result not exceeding  $0.0001 \Omega\text{m}$  taken from the probe to the electrically conductive film provided a result not exceeding  $0.0001 \Omega\text{m}$ . Comparison of this value with that measured in a case where carbon films are formed without irradiation with electrons indicated a variation exceeding two places.